Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/682,641	CHANG ET AL.
Examiner	Art Unit
Hiep T. Nguyen	2187

	SEARCHED					
Class	Subclass	Date	Examiner			
711	103	Text 1	elastes			
	170	using	EAST			
	156	0				
365	156 185.09					
	1					

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	1				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
EPIST search luss is attached	3/19/06	3/19/0			
NPL search wing terms similar to EAST search.		145			
Inventorship Jearch					